

DIMENSION ® 2000 AND CUSTOM PBX  
NETWORK I/O TESTS  
(PROC 505)

*the 4 MHz cables  
send and receive signals  
to the other cabinets  
this test checks the  
packs and cables*

CONTENTS

1. GENERAL
2. RECORDS
3. MAAP DISPLAY FIELDS
4. MAAP CONTROL KEY SEQUENCES
5. PROCEDURES
6. TROUBLESHOOTING AIDS

---

1. GENERAL

- 1.1 This section provides information for interrogating PROC 505 in the event that the craftsperson is directed to this procedure due to a NETWORK I/O failure. Whenever this type of alarm occurs, the ALARM PANEL - MAJOR and NETWORK I/O LED'S will be lit.

2. RECORDS

- 2.1 Form SD 97-1313 is required for recording the results of this test.

PRIVATE

Printed in U.S.A.

THE INFORMATION CONTAINED HEREIN SHOULD NOT BE DISCLOSED TO UNAUTHORIZED PERSONS. IT IS MEANT SOLELY FOR USE BY AUTHORIZED BELL SYSTEM EMPLOYEES.

3. MAAP DISPLAY FIELDS (PROC 505 FORMAT)

3.1 The following describes each of the display fields for the NETWORK I/O tests (PROC 505) format:

FIELD DESCRIPTION

1 TEST NO - Displays active test number (maximum of 3) per the following encodes:

ENCODE DESCRIPTION

1 Displays failure history detected by on-line maintenance.  
 2 Tests all circuits sequentially.  
 3 Tests a particular circuit (as displayed in FIELDS 2 and 3).

2,3 NET I/O INTFC EQUIP. LOC. (MODULE/CAB) - (TESTS 1, 2, and 3), for TESTS 1 and 2, displays fault location. For TEST 3, displays test location. Allowable encodes are as follows:

ENCODE DESCRIPTION

00 - MM Allowable encodes for FIELD 2, (MM= highest module number in system under test).  
 0 - C Allowable encodes for FIELD 3, (C= highest cabinet number in module under test).

4,5 NET I/O INTFC. EQUIP. LOC. (SUB CHAN/DATA CON) - (TESTS 1, 2, and 3), for TESTS 1 and 2, FIELD 4 displays sub channel circuit (LC123) and FIELD 5 displays data controller circuit (LC124) associated with faultly high speed data channel. For TEST 3, displays location of LC123 and LC124 associated with high speed data channel under test.

6 COMMON CONTROL EQUIPMENT LOCATION - CHAN CONT/CARR TYPE - (TESTS 1, 2, and 3), for TESTS 1 and 2, displays channel controller carrier type associated with faultly high speed data channel per the following encodes:

- | <u>ENCODE</u> | <u>DESCRIPTION</u>   |
|---------------|--|
| 0             | Basic control carrier  |
| 1             | Growth control carrier   |
| 7             | COMMON CONTROL EQUIPMENT LOCATION - CHAN<br>CONT/SLOT - (TESTS 1, 2, and 3), for TESTS 1 and 2,<br>displays location of channel controller circuit (LC130)<br>associated with faultly high speed data channel. For TEST<br>3, displays location circuit (LC130) location of high speed<br>data channel under test. The encodes are as follows: |

- | <u>ENCODE</u> | <u>DESCRIPTION</u>  |
|---------------|---|
| 39            | Basic control carrier - channel controller location   |
| 34, 37        | Growth control carrier - channel controller<br>locations  |
| 8             | COMMON CONTROL EQUIPMENT LOCATION - SUB CHANNEL<br>/CARR TYPE - (TESTS 1, 2 and 3), for TESTS 1 and 2 displays<br>location of sub channel carrier associated with faultly<br>high speed data channel. For TEST 3, displays carrier<br>location of sub channel carrier under test. |

- | <u>ENCODE</u> | <u>DESCRIPTION</u>   |
|---------------|--|
| 0             | Basic control carrier  |
| 1             | Growth control carrier   |
| 9             | COMMON CONTROL EQUIPMENT LOCATION - SUB<br>CHANNEL/SLOT - (TESTS 1, 2, and 3), for TESTS 1 and<br>2, displays location of sub channel circuit associated with<br>faultly high speed data channel. For TEST 3, displays circuit<br>location of sub channel circuit under test. The encodes<br>are as follows: |

- | <u>ENCODE</u> | <u>DESCRIPTION</u>   |
|---------------|--|
| 40            | Basic control carrier sub channel circuit pack<br>location   |
| 35,36         | Growth control carrier sub channel   |
| 38,39         | Circuit pack locations   |
| 10            | COMMON CONTROL EQUIPMENT LOCATION - SUB<br>CHANNEL/CIRCUIT - (TESTS 1, 2, and 3), for TESTS<br>1 and 2, displays location of sub channel circuit (in LC131)<br>associated with faultly high speed data channel. For TEST |

3, displays location of sub channel circuit under test. The encodes are as follows:

<u>ENCODE</u>	<u>DESCRIPTION</u>
0 - 7	Sub channel circuit in LC131

- 11 FAILURE CODE - (TESTS 1, 2, and 3), displays detected high speed data channel failure code. The encodes are as follows:

<u>ENCODE</u>	<u>DESCRIPTION</u>
0	Pass (TEST 3 only)
1	LC130 addressing (write)
2	LC130 addressing (read)
3	LC130 echo mismatch
4	LC123, LC124 and LC131 addressing (write)
5	LC123, LC124 and LC131 addressing (read)
6	LC123, LC124 and LC131 echo mismatch

- 12 NUMBER OF NETWORK INTERFACE CIRCUITS - (TESTS 1, 2, and 3), displays total number of system high speed data channel circuits activated.

- 13 NUMBER OF NETWORK INTERFACE CIRCUIT FAILURES - (TESTS 1 and 2), for TEST 1, displays total number of high speed data channel circuit failures detected by on-line maintenance. For TEST 2, displays total number of high speed data channel failures detected by TEST 2.

- 14 FAILURE INDEX - (TESTS 1 and 2), displays an index number which either indicates:  
 A) Locations with highest number of failures in descending order (TEST 1), or  
 B) Locations in order of detected failures (TEST 2).  
 Index number "0" in TEST 1, indicates a display of the total number of failures detected by on-line maintenance; in TEST 2, indicates that no failures were detected.

#### 4. MAAP CONTROL KEY SEQUENCES

- 4.1 PROC NO. 5, 0, 5, ENTER - causes program for PROC 505 to be loaded into memory from tape for execution.
- 4.2 CLEAR DATA, EXECUTE - (TEST 1), clears failure history records stored in memory.
- 4.3 EXECUTE - executes test number displayed in FIELD 1.
- 4.4 NEXT CIRCUIT - for TESTS 1 and 2, displays next failure. For TEST 3, advances test to next equipped cabinet when test is stopped.
- 4.5 NEXT TEST - advances procedure to the next test.
- 4.6 NEXT UNIT - (TEST 3), advances test to the next module when test is stopped.
- 4.7 RESET - resets the procedure to the beginning of TEST 1.
- 4.8 STOP - stops TEST 3 from further testing. NOTE: This key must be operated before the NEXT CIRCUIT or NEXT UNIT key can be operated if TEST 3 is executing.

#### 5. REPAIR PROCEDURES

- 5.1 The following describes the repair procedures that should be used in the event of a NETWORK I/O Alarm.
  - 5.1.1 Execute TEST 1 and record failure history generated by on-line maintenance.
  - 5.1.2 Execute TEST 2 and record the results. If there are no failures, use TEST 3 to continuously test each cabinet displayed in TEST 1 to check for intermittent failures. If failures occur either during TEST 2 or 3, use the following repair procedures:
    - A) FAILURE CODE = 1, 2, 3, or 4 - go to PROC 501
    - B) FAILURE CODE = 5 or 6 - if more than one NETWORK I/O failure is indicated go to STEP C, otherwise, do the following:
      - FIRST - Replace LC123 and execute TEST 2. If TEST 2 passes, go to STEP E, otherwise, reinsert old LC123.

- SECOND- Replace LC124 and execute TEST 2. If TEST 2 passes, go to STEP E, otherwise, reinsert old LC124.
- THIRD - Replace LC131 (use HALT/GO sequence) and execute TEST 2. If TEST 2 passes, go to STEP E, otherwise, reinsert old LC131 (use HALT/GO sequence).
- FOURTH- Replace LC121 (see attachment 1). If TEST 2 passes, go to STEP E.
- FIFTH - If none of the above clears the alarm, replace all of the above circuit packs and execute TEST 2. If TEST 2 passes, go to STEP E otherwise, check for possible wiring problem (see Paragraph 6 of this section).

*do a new 2000 installation check the 4 MAZ cables for shorts + opens this is the most likely problem*

C) Use the following when more than one NETWORK I/O circuit failure is indicated, all of which utilize the same common control equipment location, otherwise, go to STEP D:

- FIRST -- Replace indicated LC131 (use halt/go sequence and execute TEST 2. If TEST 2 passes go to STEP E, otherwise, reinsert old LC131 (use HALT/GO sequence).
- SECOND- Replace indicated LC130 (use HALT/GO sequence) and execute TEST 2. If TEST 2 passes, go to STEP E, otherwise, replace LC131 again and execute TEST 2. If test passes, go to STEP E, or if test fails, refer to Paragraph 6 of this section.

- D) If all circuit failures are common to one module, there may be a defective LC121. Use Flowchart - Attachment 1 - to find defective LC121 and if this is not successful, refer to Paragraph 6 of this section.
- E) In the event that the NETWORK I/O Alarm is cleared, go to TEST 1 and clear the fault records - use CLEAR DATA, EXECUTE keys.

5.1.3 After the trouble(s) has been cleared, go to TEST 1 and clear the on-line maintenance records. Use CLEAR DATA, EXECUTE keys.

## 6. TROUBLESHOOTING AIDS

### 6.1 GENERAL TEST INFORMATION

- 6.1.1 TEST 1 - TEST 1 is the default test when the procedure is first read in from the tape or when the MAAP-RESET key is operated. In either case, FIELD 1 will display a 1 and FIELD 12 will display the total number of network interface circuits. When the MAAP-EXECUTE key is operated, data accumulated by on-line maintenance is displayed on the MAAP. If there are no failures, FIELD 13 will display a "0" and if there are one or more failures, FIELD 13 will display a "1" (indicating the lowest numbered NETWORK I/O where a failure was detected) and FIELDS 2 thru 11 will display the appropriate failure information.

Operation of the MAAP-NEXT CIRCUIT key displays the next higher numbered NETWORK I/O where a failure was detected. If there are no more failures to be displayed or if six failures have been displayed (maximum number of failures that can be displayed in this test), all fields except 1 and 12 are dashed.

Operation of the MAAP-CLEAR DATA, EXECUTE keys clears the on-line maintenance NETWORK I/O failure records.

- 6.1.2 TEST 2 - The purpose of TEST 2 is to test all NETWORK I/O CHANNELS sequentially, to display all the failed circuits and to control the ALARM PANEL-MAJOR and NETWORK I/O alarms.

TEST 2 is initiated when the MAAP-EXECUTE key is operated, which causes the MAAP-WAIT to be turned on, puts the system into a loop around mode and tests the LC130 circuit associated with the NETWORK I/O CHANNEL to be tested. If a failure is detected, the system is taken out of loop around mode, the MAAP-WAIT lamp is turned off, and the appropriate failure information is displayed on the MAAP.

If the above test passes, the system is taken out of the loop around mode and the LC131, LC123, LC124 circuits associated with the NETWORK I/O CHANNEL are tested. If a failure is detected, the failure information is stored for future display and the test continues to the next NETWORK I/O circuits.

are tested and if there are no failures detected FIELD 13 will display a "0". If one or more failures were detected when the test is completed, FIELDS 2 thru 11 will display the appropriate failure information for the first failure detected, FIELD 13 will display the total number of circuit failures and FIELD 14 will display a "1".

Repeated operation of the MAAP-NEXT CIRCUIT key will display the other detected failures and if last failure was displayed, operation of the NEXT CIRCUIT key will cause FIELDS 2 thru 12, 13 and 14 to be dashed.

If during the execution of this test, no failures are detected, the ALARM PANEL-MAJOR and NETWORK I/O lamps will turn off if they were on.

- 6.1.3 TEST 3 - The purpose of TEST 3 is to test a particular circuit continuously and to turn the ALARM PANEL MAJOR and NETWORK I/O on if a failure is detected. If a default circuit (last failure displayed) is not displayed, the craftsperson must enter a circuit. If the displayed circuit is not the circuit desired, it can be changed by the change field sequence, or by operating the NEXT CIRCUIT key (advances to the next circuit within the specified module), or by operating the next unit key (advances to the next module).

The test is started by operating the MAAP-EXECUTE key. The WAIT lamp is not turned on since the test is continuous. The failure code is flashed (60 IPM) in FIELD 11 to indicate that the test is running. The test can be stopped by either operating the STOP key (which then allows a NEXT CIRCUIT or a NEXT UNIT key operation) or operating the NEXT TEST, RESET, or PROC NO. keys.

## 6.2 GENERAL TROUBLESHOOTING INFORMATION

- 6.2.1 PROC 505 checks the High Speed Network Data Channel circuits by (1) first setting the loop test (LPTST) flip flop in LC133, to cause data sent, to be looped back at the LC130 circuit pack under test and (2) resetting the loop test flip flop in LC133 and sending data to the NETWORK I/O circuits which will be looped back and checked.

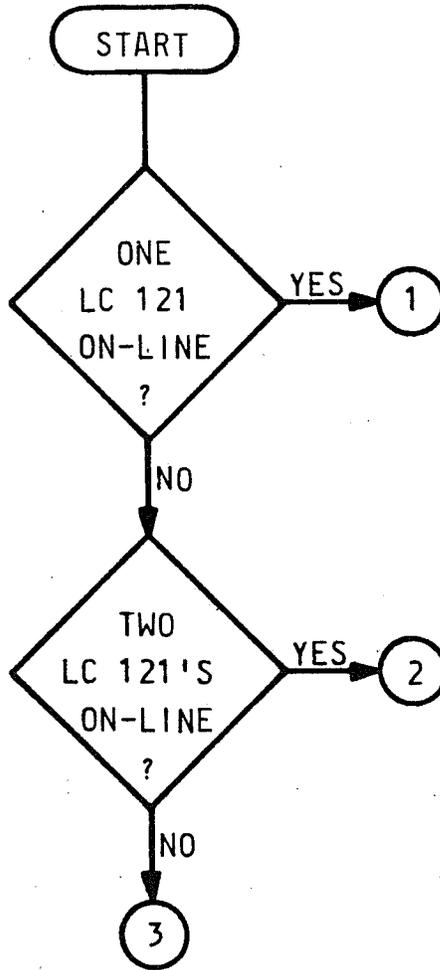
When the LC130 is set to the loop around mode, the addresses used will be that of the NETWORK I/O CHANNEL to be tested and the data sent will be 0000, FFFF, AAAA, 5555. The data

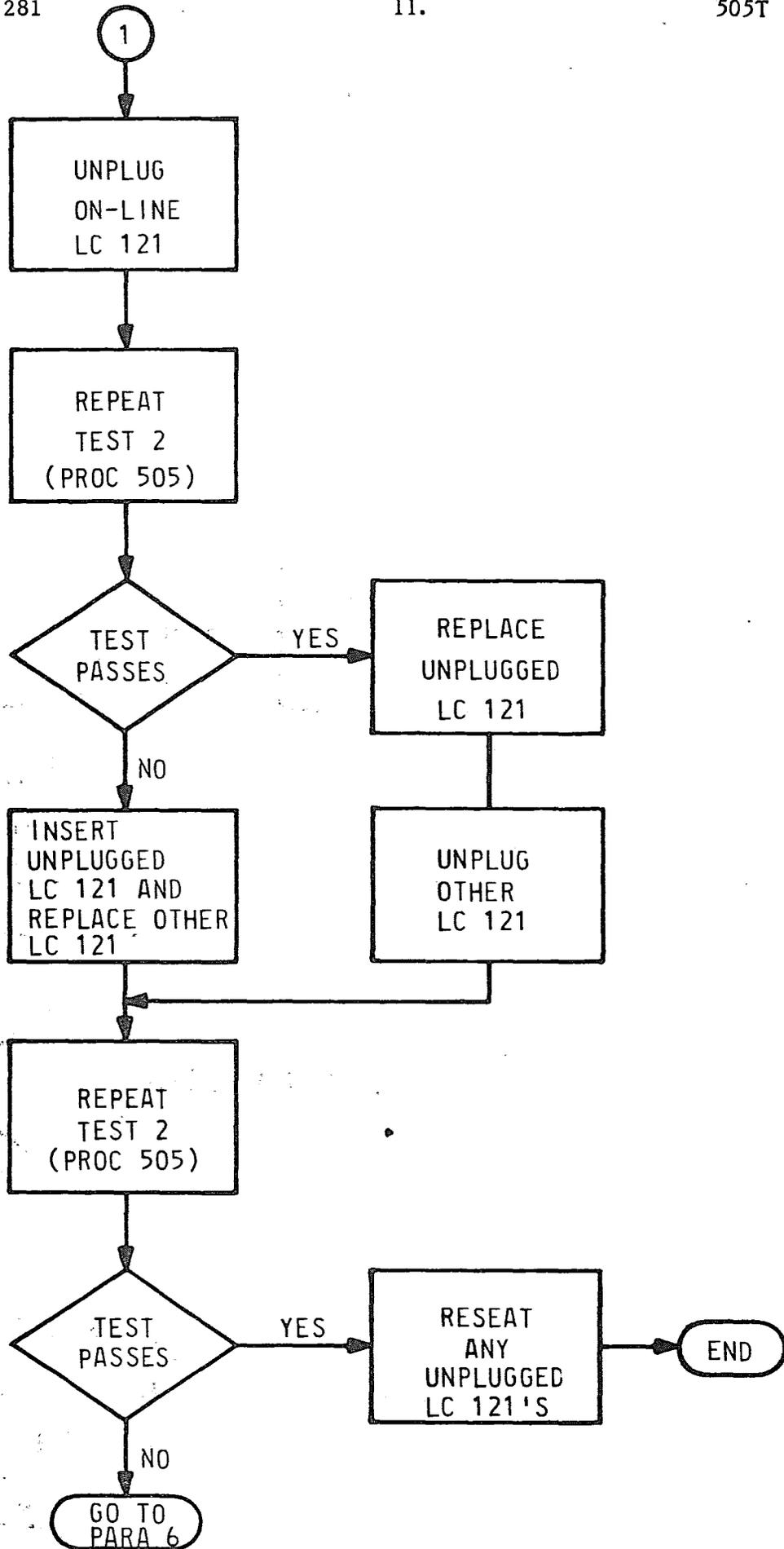
received is checked to see that it is the same as was sent. If a failure is detected, the appropriate fail code is displayed.

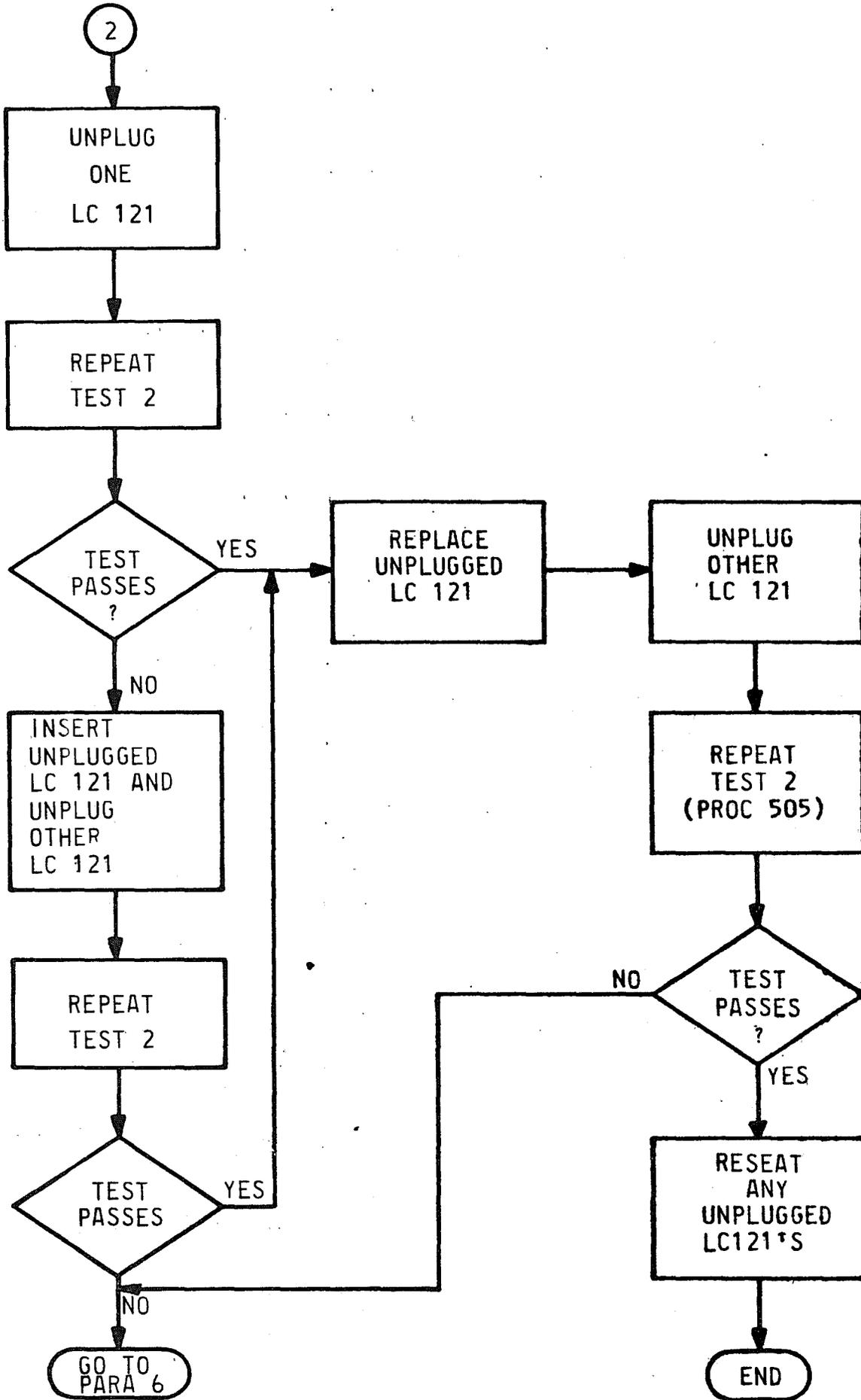
If the first test passes, the associated LC131, LC123, and LC124 NETWORK I/O circuits are tested. The address used will be that of the particular NETWORK I/O CHANNEL under test and the data sent will be 0555, 02AA, 1D55 and 1AAA. Each data pattern received is verified to see that it is the same as was sent.

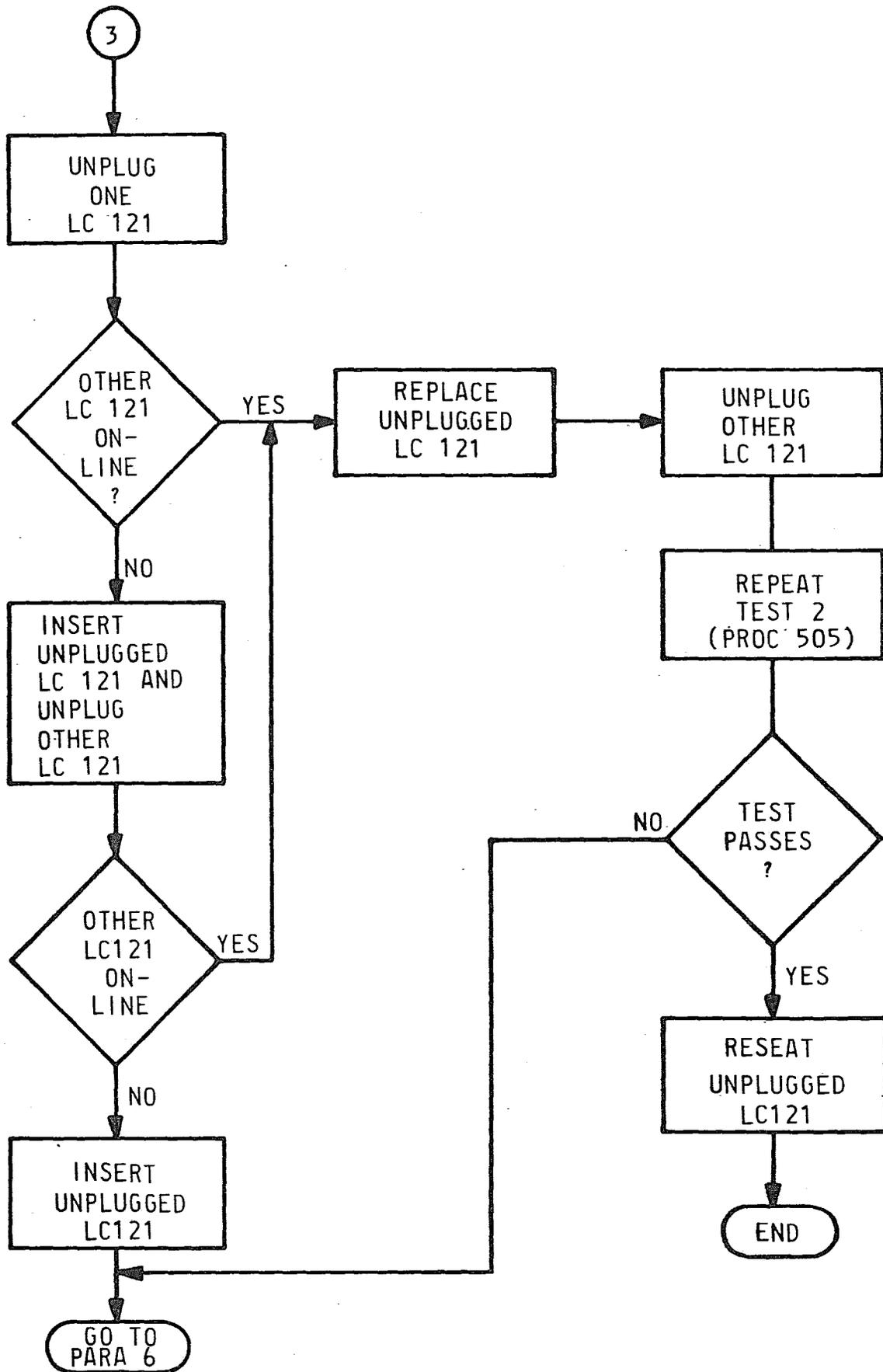
The following describes possible causes to failure codes displayed in FIELD 11.

<u>ENCODE</u>	<u>DESCRIPTION</u>
1	Failure to receive an I/O DONE signal during a write operation while the LC130 is in loop around.
2	Failure to receive an I/O DONE signal during a read operation while the LC130 is in loop around.
3	Failure to receive correct data response while the LC130 is in loop around.
4	Failure to receive an I/O DONE signal from LC130 during a write operation to the NETWORK I/O CHANNEL.
5	Failure to receive an I/O DONE signal plus a 17 bit message with correct polarity during a read operation.
6	Failure to receive the same data message as was sent to the NETWORK I/O CHANNEL.





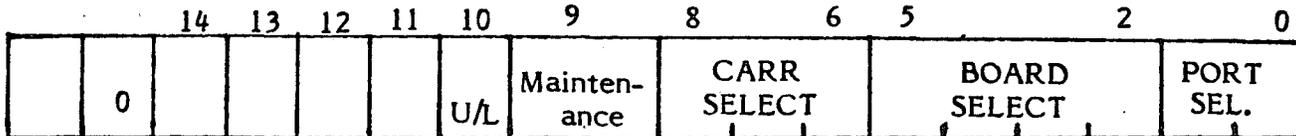




**NETWORK COMMANDS**

- :Time slot commands.
- :Data Distribution commands.
- :Scan commands.

1. Scanner/distributor operation (address)
2. Network command (address)
3. Network/distribution (data)
4. Scanner/distributor scan command
5. Network status



Type of I/O:

- 11 - Store Data Field and Reset
- 10 - Generate a WRIO
- 01 - Generate a RDIO

- 11 - Data Field is Data for WRIO
- 01 - Data Field is Address for Network Op.
- 10 - Data Field is Address for Scan/Dist. Op.

Always Zero

SEE SD-1E480

## 4 MHZ DATA CHANNEL

DATA CHANNEL ADDRESS (OCTAL)	CHANNEL NO. SD.	LC-130 SLOT	LC-131 SLOT	DESTINATION		PROCESSOR Ø CABLES				PROCESSOR 1 CABLES				DATA CHANNEL ADDRESS (HEX)
				MOD	CAB	FROM		TO		FROM		TO		
						CARR	DESIG	CARR	DESIG	CARR	DESIG	CARR	DESIG	
000	0000	39	40	00	0	AA	BHS1	BA	MC42	AA	BHS1	BA	MC41	6000
001	0001	39	40	00	1	AA	BHS1	BA	MC42	AA	BHS1	BA	MC41	6001
002	0002	39	40	00	2	AA	BHS1	BB	LG27	AA	BHS1	BB	LG24	6002
003	0003	39	40	00	3	AA	BHS1	BB	LG27	AA	BHS1	BB	LG24	6003
004	0004	39	40	00	4	AA	BHS2	BB	LG27	AA	BHS2	BB	LG24	6004
005	0005	39	40	01	0	AA	BHS2	BA	MC42	AA	BHS2	BA	MC41	6005
006	0006	39	40	01	1	AA	BHS2	BA	MC42	AA	BHS2	BA	MC41	6006
007	0007	39	40	01	2	AA	BHS2	BB	LG27	AA	BHS2	BB	LG24	6007
010	0008	39	40	01	3	AA	BHS3	BB	LG27	AA	BHS3	BB	LG24	6008
011	0009	39	40	01	4	AA	BHS3	BB	LG27	AA	BHS3	BB	LG24	6009
012	0010	39	40	02	0	AA	BHS3	BA	MC42	AA	BHS3	BA	MC41	600A
013	0011	39	40	02	1	AA	BHS3	BA	MC42	AA	BHS3	BA	MC41	600B
014	0012	39	40	02	2	AA	BHS4	BB	LG27	AA	BHS4	BB	LG24	600C
015	0013	39	40	02	3	AA	BHS4	BB	LG27	AA	BHS4	BB	LG24	600D
016	0014	39	40	02	4	AA	BHS4	BB	LG27	AA	BHS4	BB	LG24	600E
017	0015	39	40	03	0	AA	BHS4	BA	MC42	AA	BHS4	BA	MC41	600F
100	1000	34	35	03	1	AB	GHS1	BA	MC42	AB	GHS1	BA	MC41	6040
101	1001	34	35	03	2	AB	GHS1	BB	LG27	AB	GHS1	BB	LG24	6041
102	1002	34	35	03	3	AB	GHS1	BB	LG27	AB	GHS1	BB	LG24	6042
103	1003	34	35	03	4	AB	GHS1	BB	LG27	AB	GHS1	BB	LG24	6043
104	1004	34	35	04	0	AB	GHS2	BA	MC42	AB	GHS2	BA	MC41	6044
105	1005	34	35	04	1	AB	GHS2	BA	MC42	AB	GHS2	BA	MC41	6045
106	1006	34	35	04	2	AB	GHS2	BB	LG27	AB	GHS2	BB	LG24	6046
107	1007	34	35	04	3	AB	GHS2	BB	LG27	AB	GHS2	BB	LG24	6047

DATA CHANNEL ADDRESS (OCTAL)	CHANNEL NO. SD.	LC-130 SLOT	LC-131 SLOT	DESTINATION		PROCESSOR 0		CABLES		PROCESSOR 1		CABLES		DATA CHANNEL ADDRESS (HEX)
				MOD	CAB	FROM		TO		FROM		TO		
						CARR	DESIG	CARR	DESIG	CARR	DESIG	CARR	DESIG	
110	1008	34	35	04	4	AB	GHS2	BB	LG27	AB	GHS2	BB	LG24	6048
111	1009	34	35	05	0	AB	GHS3	BA	MC42	AB	GHS3	BA	MC41	6049
112	1010	34	35	05	1	AB	GHS3	BA	MC42	AB	GHS3	BA	MC41	604A
113	1011	34	35	05	2	AB	GHS3	BB	LG27	AB	GHS3	BB	LG24	604B
114	1012	34	35	05	3	AB	GHS3	BB	LG27	AB	GHS3	BB	LG24	604C
115	1013	34	35	05	4	AB	GHS4	BB	LG27	AB	GHS4	BB	LG24	604D
116	1014	34	35	06	0	AB	GHS4	BA	MC42	AB	GHS4	BA	MC41	604E
117	1015	34	35	06	1	AB	GHS4	BA	MC42	AB	GHS4	BA	MC41	604F
120	1100	34	36	06	2	AB	GHS4	BB	LG27	AB	GHS4	BB	LG24	6050
121	1101	34	36	06	3	AB	GHS5	BB	LG27	AB	GHS5	BB	LG24	6051
122	1102	34	36	06	4	AB	GHS5	BB	LG27	AB	GHS5	BB	LG24	6052
123	1103	34	36	07	0	AB	GHS5	BA	MC42	AB	GHS5	BA	MC41	6053
124	1104	34	36	07	1	AB	GHS5	BA	MC42	AB	GHS5	BA	MC41	6054
125	1105	34	36	07	2	AB	GHS6	BB	LG27	AB	GHS6	BB	LG24	6055
126	1106	34	36	07	3	AB	GHS6	BB	LG27	AB	GHS6	BB	LG24	6056
127	1107	34	36	07	4	AB	GHS6	BB	LG27	AB	GHS6	BB	LG24	6057
130	1108	34	36	08	0	AB	GHS6	BA	MC42	AB	GHS6	BA	MC41	6058
131	1109	34	36	08	1	AB	GHS7	BA	MC42	AB	GHS7	BA	MC41	6059
132	1110	34	36	08	2	AB	GHS7	BB	LG27	AB	GHS7	BB	LG24	605A
133	1111	34	36	08	3	AB	GHS7	BB	LG27	AB	GHS7	BB	LG24	605B
134	1112	34	36	08	4	AB	GHS7	BB	LG27	AB	GHS7	BB	LG24	605C
135	1113	34	36	09	0	AB	GHS8	BA	MC42	AB	GHS8	BA	MC41	605D
136	1114	34	36	09	1	AB	GHS8	BA	MC42	AB	GHS8	BA	MC41	605E
137	1115	34	36	09	2	AB	GHS8	BB	LG27	AB	GHS8	BB	LG24	605F

SEE SD-1E480

## 4 MHZ DATA CHANNEL

DATA CHANNEL ADDRESS (OCTAL)	CHANNEL NO. SD.	LC-130 SLOT	LC-131 SLOT	DESTINATION		PROCESSOR Ø		CABLES		PROCESSOR 1		CABLES		DATA CHANNEL ADDRESS (HEX)
				MOD	CAB	FROM		TO		FROM		TO		
						CARR	DESIG	CARR	DESIG	CARR	DESIG	CARR	DESIG	
140	1200	37	38	09	3	AB	GHS8	BB	LG27	AB	GHS8	BB	LG24	6060
141	1201	37	38	09	4	AB	GHS9	BB	LG27	AB	GHS9	BB	LG24	6061
142	1202	37	38	10	0	AB	GHS9	BA	MC42	AB	GHS9	BA	MC41	6062
143	1203	37	38	10	1	AB	GHS9	BA	MC42	AB	GHS9	BA	MC41	6063
144	1204	37	38	10	2	AB	GHS9	BB	LG27	AB	GHS9	BB	LG24	6064
145	1205	37	38	10	3	AB	GHS10	BB	LG27	AB	GHS10	BB	LG24	6065
146	1206	37	38	10	4	AB	GHS10	BB	LG27	AB	GHS10	BB	LG24	6066
147	1207	37	38	11	0	AB	GHS10	BA	MC42	AB	GHS10	BA	MC41	6067
150	1208	37	38	11	1	AB	GHS10	BA	MC42	AB	GHS10	BA	MC41	6068
151	1209	37	38	11	2	AB	GHS11	BB	LG27	AB	GHS11	BB	LG24	6069
152	1210	37	38	11	3	AB	GHS11	BB	LG27	AB	GHS11	BB	LG24	606A
153	1211	37	38	11	4	AB	GHS11	BB	LG27	AB	GHS11	BB	LG24	606B
154	1212	37	38	12	0	AB	GHS11	BA	MC42	AB	GHS11	BA	MC41	606C
155	1213	37	38	12	1	AB	GHS12	BA	MC42	AB	GHS12	BA	MC41	606D
156	1214	37	38	12	2	AB	GHS12	BB	LG27	AB	GHS12	BB	LG24	606E
157	1215	37	38	12	3	AB	GHS12	BB	LG27	AB	GHS12	BB	LG24	606F
160	1300	37	39	12	4	AB	GHS12	BB	LG27	AB	GHS12	BB	LG24	6070
161	1301	37	39	13	0	AB	GHS13	BA	MC42	AB	GHS13	BA	MC41	6071
162	1302	37	39	13	1	AB	GHS13	BA	MC42	AB	GHS13	BA	MC41	6072
163	1303	37	39	13	2	AB	GHS13	BB	LG27	AB	GHS13	BB	LG24	6073
164	1304	37	39	13	3	AB	GHS13	BB	LG27	AB	GHS13	BB	LG24	6074
165	1305	37	39	13	4	AB	GHS14	BB	LG27	AB	GHS14	BB	LG24	6075
166	1306	37	39	14	0	AB	GHS14	BA	MC42	AB	GHS14	BA	MC41	6076
167	1307	37	39	14	1	AB	GHS14	BA	MC42	AB	GHS14	BA	MC41	6077

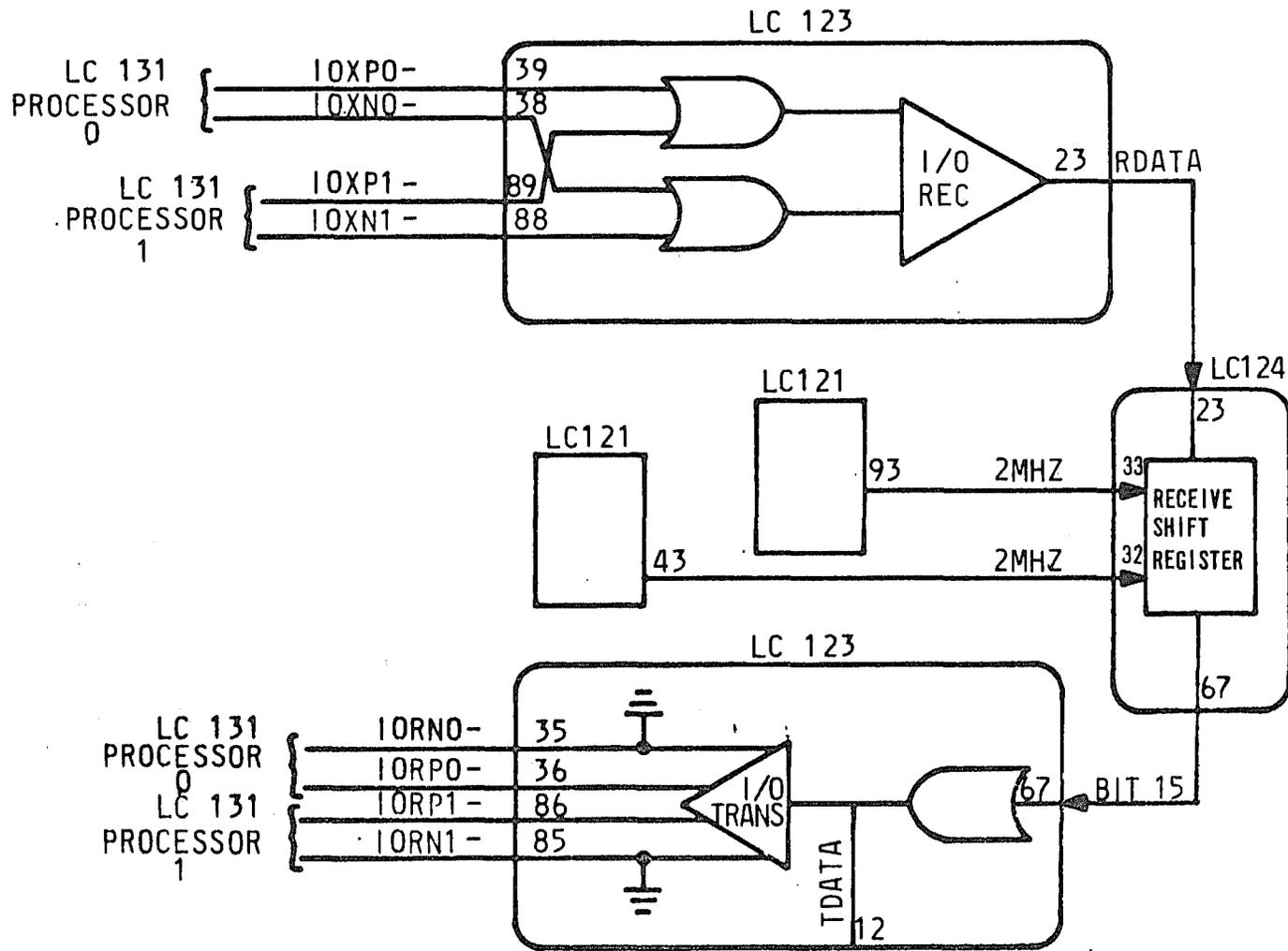
HB 281

17.

505T



PROC 505  
LC 123, 124: LOOP AROUND



<p><b>TEST 1:</b> DISPLAYS FAILURE HISTORY. USE 'NEXT CIRCUIT' TO DISPLAY NEXT FAILED NETWORK INTERFACE CIRCUIT. USE 'CLEAR DATA', 'EXECUTE' TO CLEAR FAILURE HISTORY.</p>	<p><b>TEST 2:</b> TESTS ALL CIRCUITS. USE 'NEXT CIRCUIT' TO DISPLAY NEXT CIRCUIT FAILURE.</p>	<p><b>TEST 3:</b> TESTS A PARTICULAR CIRCUIT CONTINUOUSLY. USE 'NEXT CIRCUIT' TO ADVANCE TO NEXT CIRCUIT. USE 'NEXT UNIT' TO ADVANCE TO NEXT MODULE.</p>	<p><b>NOTES:</b> 1. CARRIER TYPE 0=BASIC CARRIER 1=GROWTH CARRIER</p>	<p><b>COMMON CONTROL LOOP AROUND FAIL CODES (FLD 11):</b> 1=ADDRESSING (WRITE) 2=ADDRESSING (READ) 3=ECHO MISMATCH</p> <p><b>NETWORK I/O LOOP AROUND FAIL CODES (FLD 11):</b> 4=ADDRESSING (WRITE) 5=ADDRESSING (READ) 6=ECHO MISMATCH</p>
--	---	--	---	--

ISSUE L7.9 PROC 505

ISSUE L7.9 NETWORK I/O TESTS

TEST NO	NET I/O INTFC EQUIP. LOC.				COMMON CONTROL EQUIPMENT LOCATION					F A I L U R E C O D E	NUMBER OF NETWORK INTERFACE CIRCUITS	NUMBER OF NETWORK INTERFACE CIRCUIT FAILURES	FAILURE INDEX	PROC 505
	TEST 3		SUB CHAN	DATA CON	CHAN CONT		SUB CHANNEL							
	MODULE	CAB			CARR TYPE	SLOT	CARR TYPE	SLOT	CIRCUIT					
	1	2	3	4										

Manager, Denver PBX PECC